

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/730,910	<b>Applicant(s)/Patent under Reexamination</b>  HAN ET AL.
	<b>Examiner</b>  Hwei-Siu C. Payer	<b>Art Unit</b>  3724

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Interference		7-8-05	Payer
Search History			
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